ETR0212-004a

Voltage Detector with Delay Circuit Built-In

■GENERAL DESCRIPTION

The XC61H series is a highly accurate, low power consumption CMOS voltage detector with a delay circuit. Detect voltage is accurate with minimal temperature drift. Output configurations are available in both CMOS and N-channel open drain. Since the full delay circuit is built-in, an external delay-time capacitor is not necessary so that high density mounting is possible.

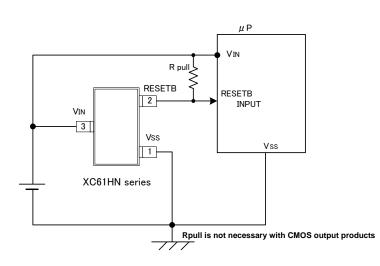
■APPLICATIONS

- Microprocessor reset circuitry
- System battery life and charge voltage monitors
- Memory battery back-up circuits
- Power-on reset circuits
- Power failure detection
- Delay circuitry

■FEATURES

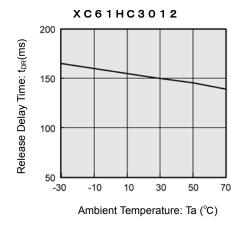
Detect Voltage Accuracy Low Power Consumption Detect Voltage Range	: ± 2% : 1.0 μ A(TYP.)[V _{IN} =2.0V] : 1.6V ~ 6.0V (0.1V increments)
Operating Voltage Range	: 0.7V ~ 10.0V
Detect Voltage Temperatu	re Characteristics
	: ±100ppm/°C(TYP.)
Built-In Release Delay tim	e : 1ms (MIN.)
	50ms (MIN.)
	80ms (MIN.)
Output Configuration	: N-ch open drain output or CMOS
Operating Ambient Temperature	e∶-30°C~80°C
Package Environmentally Friendly	: SOT-23 : EU RoHS Compliant, Pb Free

■TYPICAL APPLICATION CIRCUITS ■TYPICAL PERFORMANCE



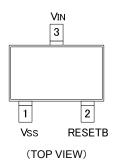
CHARACTERISTICS

●Release Delay Time (t_{DR}) vs. Ambient Temperature



XC61H Series

■ PIN CONFIGURATION



PIN NUMBER	PIN NAME	FUNCTION	
SOT-23		FUNCTION	
1	Vss	Ground	
2	RESETB	Output	
3	V _{IN}	Supply Voltage Input	

■ PIN ASSIGNMENT

■ PRODUCT CLASSIFICATION

Ordering Information

XC61H1234567-8(*1)

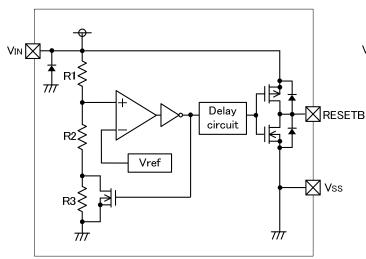
DESIGNATOR	ITEM	SYMBOL	DESCRIPTION
1	Output Configuration	С	CMOS output
U	Output Configuration	N	N-ch open drain output
23	Detect Voltage (VDF)	16 ~ 60	e.g. 2.5V → ②2 , ③5
		1	50ms ~ 200ms
4	Release Delay Time	4	80ms ~ 400ms
		5	1ms ~ 50ms
5	Detect Accuracy	2	± 2.0% ^(*2)
67-8(*1)	Package (Oder Unit)	MR-G	SOT-23 (3000pcs/Reel)

(*1) The "-G" suffix indicates that the products are Halogen and Antimony free as well as being fully RoHS compliant.

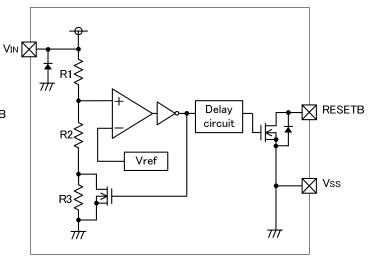
(*2) No parts are available with an accuracy of $\pm\,1\%$

BLOCK DIAGRAMS

(1)CMOS output



(2)N-ch open drain output



■ABSOLUTE MAXIMUM RATINGS

PAR	AMETER	SYMBOL	RATINGS	UNITS	
Inpu	it Voltage	V _{IN}	V _{SS} -0.3 ~ 12.0	V	
Outp	ut Current	Іоит	50	mA	
Output Voltage	CMOS	\/	V _{SS} -0.3 ~V _{IN} +0.3	V	
	N-ch open drain output	VRESETB	Vss -0.3 ~ 12		
Power Dissipation SOT-23		Pd	250	mW	
Operating Am	bient Temperature	Topr	-30~+80	°C	
Storage	Temperature	Tstg	-40~+125	°C	

■ ELECTRICAL CHARACTERISTICS

Ta = 25°C

PARA	AMETER	SYMBOL	CONDITIO	ONS	MIN.	TYP.	MAX.	UNITS	CIRCUIT
Detec	t Voltage	V_{DF}			V _{DF(T)} x 0.98	V _{DF(T)}	V _{DF(T)} x 1.02	V	1
Hyster	esis Width	VHYS			V _{DF} x 0.02	V _{DF} x 0.05	V _{DF} x 0.08	V	1
				V _{IN} = 1.5V	-	0.9	2.6		
				V _{IN} = 2.0V	-	1.0	3.0		
Supply	Current (*1)	lss		V _{IN} = 3.0V	-	1.3	3.4	μA	2
				V _{IN} = 4.0V	-	1.6	3.8		
				V _{IN} = 5.0V	-	2.0	4.2		
Operati	ng Voltage	V _{IN}	V _{DF} =1.6V~6.0V		0.7	-	10.0	V	1
				V _{IN} = 1.0V	1.0	2.2	-	mA	3
		Ιουτ	N-ch, V _{DS} = 0.5V	$V_{IN} = 2.0V$	3.0	7.7	-		
				V _{IN} = 3.0V	5.0	10.1	-		
Outpu	it Current			$V_{IN} = 4.0V$	6.0	11.5	-		
				V _{IN} = 5.0V	7.0	13.0	-		
			P-ch, V _{DS} =2.1V (CMOS Output)	V _{IN} = 8.0V		-10.0	-2.0		4
Leakage	CMOS Output (Pch)	ILEAK	VIN=VDF X 0.9V, VRESETB=0V		-	-0.01	-	μA	3
Current	Nch Open Drain Output		V _{IN} =10.0V, V _{RESETB} =10.0V		-	0.01	0.1		
	t Voltage Characteristics	∆V _{DF} / (∆Topr∙V _{DF})	-30°C≦Topr≦80°C		-	±100	-	ppm/°C	1
Release Delay Time (VDR → RESETB inversion)					50	-	200		
		t _{DR} VIN changes from	VIN changes from (0.6V to 10V	80	-	400	ms	(5)
					1	-	50		

Ta=25°C

VDF (T) is nominal detect voltage value Release Voltage: VDR = VDF + VHYS

(*1) The supply current during power-start until output being stable (during release operation) is 2 µ A greater with comparison to the period after the completion of release operation because of the shoot-through current in delay current.

■OPERATIONAL EXPLANATION

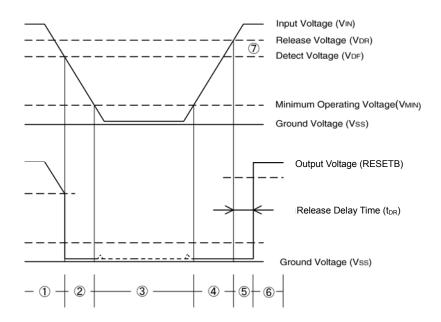
CMOS output

- An input voltage V_{IN} starts higher than the release voltage VDR. Then, V_{IN} voltage will gradually fall. When V_{IN} voltage is higher than detect voltage VDF, output voltage RESETB is equal to the VIN voltage.
 *Note that high impedance exists at RESETB with the N-channel open drain output configuration. If the RESETB pin is
- pulled up, RESETB will be equal to the pull up voltage.
 When VIN falls below VDF, RESETB will be equal to ground voltage Vss level (detect state).
- * Note that this also applies to N-channel open drain output configurations.
- 3 When VIN falls to a level below that of the minimum operating voltage VMIN, output will become unstable.
- *When the output pin is generally pulled up with N-channel open drain output configurations, output will be equal to pull up voltage.
- When VIN rises above the Vss level (excepting levels lower than minimum operating voltage), RESETB will be equal to Vss until VIN reaches the VDR level.
- 5 Although VIN will rise to a level higher than VDR, RESETB maintains ground voltage level via the delay circuit.
- 6 After taking a release delay time, VIN voltage will be output at the RESETB pin.
 *High impedance exists with the N-channel open drain output configuration and that voltage will be dependent on pull up.

Notes:

- 1. The difference between VDR and VDF represents the hysteresis width.
- 2. Release delay time (t_{DR}) represents the time it takes until when VIN voltage appears at RESETB pin once the input voltage has exceeded the VDR level.

•Timing Chart



■NOTES ON USE

- 1. Please use this IC within the stated maximum ratings. For temporary, transitional voltage drop or voltage rising phenomenon, the IC is liable to malfunction should the ratings be exceeded.
- When a resistor is connected between the V_{IN} pin and the power supply with CMOS output configurations, irregular oscillation may occur as a result of voltage drops at R_{IN} if load current (I_{OUT}) exists. It is therefore recommend that no resistor be added. (refer to Figure 1 below)
- 3. When a resistor (R_{IN}) is connected between the V_{IN} pin and the power supply with CMOS output configurations, irrespective of N-ch open drain output configurations, oscillation may occur as a result of shoot-through current at the time of voltage release even if load current (I_{OUT}) does not exist. (refer to Figure 2 below)
- 4. If a resistor (R_{IN}) must be used, then please use with as small a level of input impedance as possible in order to control the occurrences of oscillation as described above. Further, please ensure that R_{IN} is less than 10kΩ and that C_{IN} is more than 0.1 μF, please test with the actual device. However, N-ch open drain output only. (Figure 1).
- 5. With a resistor RIN connected between the V_{IN} pin and the power supply, the V_{IN} pin voltage will be getting lower than the power supply voltage as a result of the IC's supply current flowing through the V_{IN} pin.
- 6. Depending on circuit's operation, release delay time of this IC can be widely changed due to upper limits or lower limits of operational ambient temperature.
- 7. Torex places an importance on improving our products and its reliability.
- However, by any possibility, we would request user fail-safe design and post-aging treatment on system or equipment.

Irregular Oscillations

(1) Irregular oscillation as a result of load current with the CMOS output configuration:

When the voltage applied at power supply, release operations commence and the detector's output voltage increases. Load current (I_{OUT}) will flow through R_L. Because a voltage drop ($R_{IN} \times I_{OUT}$) is produced at the R_{IN} resistor, located between the power supply and the V_{IN} pin, the load current will flow via the IC's VIN pin. The voltage drop will also lead to a fall in the voltage level at the V_{IN} pin. When the V_{IN} pin voltage level falls below the detect voltage level, detect operations will commence. Following detect operations, load current flow will cease and since voltage drop at R_{IN} will disappear, the voltage level at the V_{IN} pin will rise and release operations will begin over again. Irregular oscillation may occur with this "release - detect - release" repetition.

Further, this condition will also appear via means of a similar mechanism during detect operations.

(2) Irregular oscillation as a result of shoot-through current:

Since the XC61H series are CMOS ICs, shoot-through current will flow when the IC's internal circuit switching operates (during release and detect operations). Consequently, irregular oscillation is liable to occur during release voltage operations as a result of output current which is influenced by this shoot-through current (Figure 3). Since hysteresis exists during detect operations, irregular oscillation is unlikely to occur.

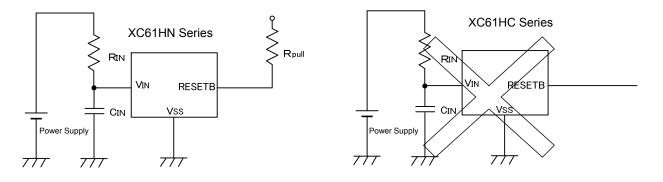
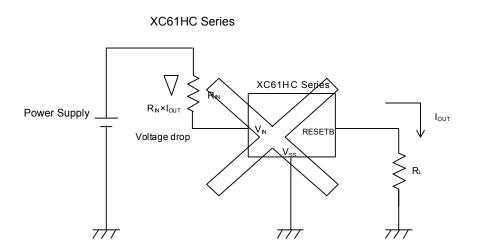


Figure 1 Use of input resistor RIN

■NOTES ON USE (Continued)

Irregular Oscillations (Continued)





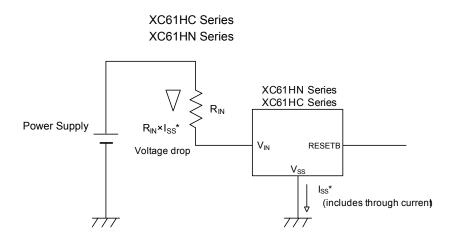
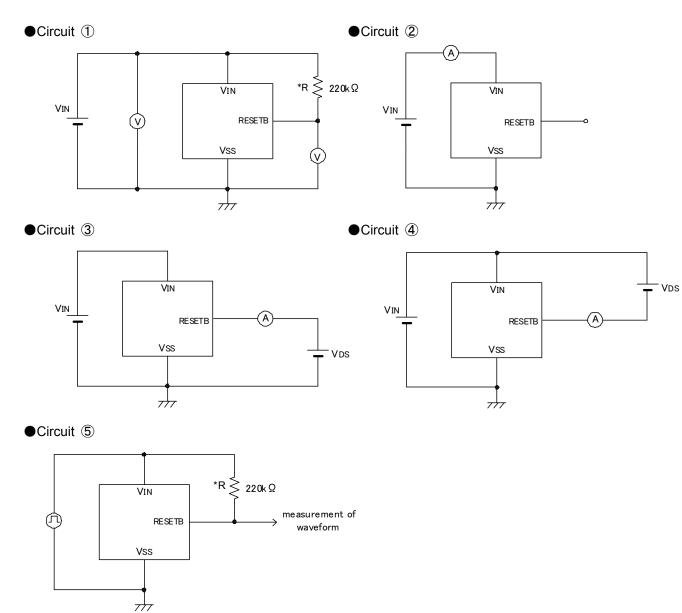


Figure 3 Irregular Oscillation by shoot-through current

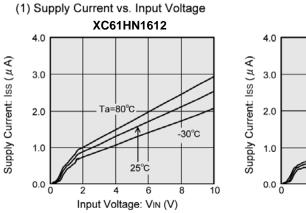
■TEST CIRCUITS

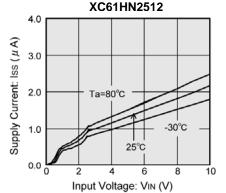


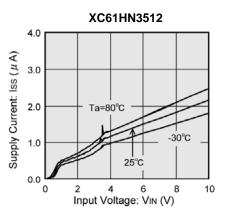
*R is not necessary with CMOS output products.

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■ TYPICAL PERFORMANCE CHARACTERISTICS



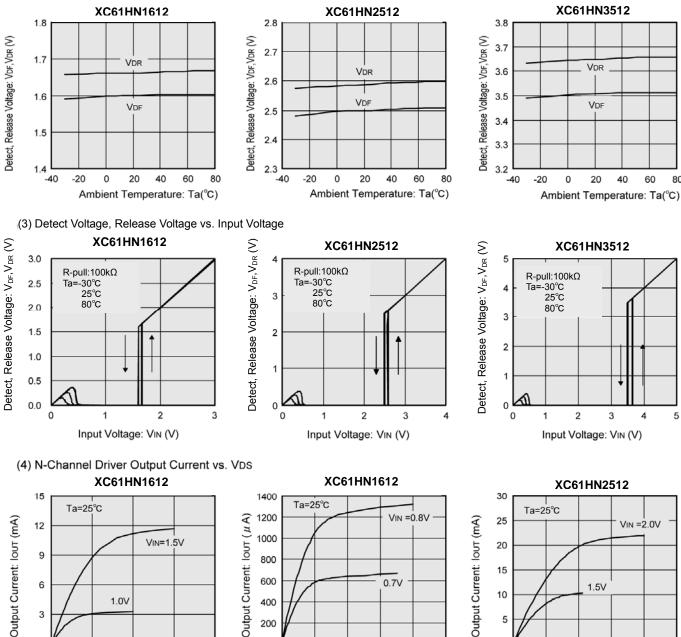


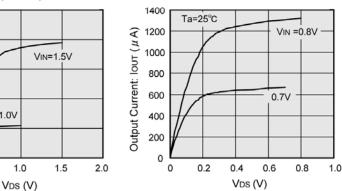


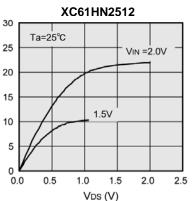
80

5









9

6

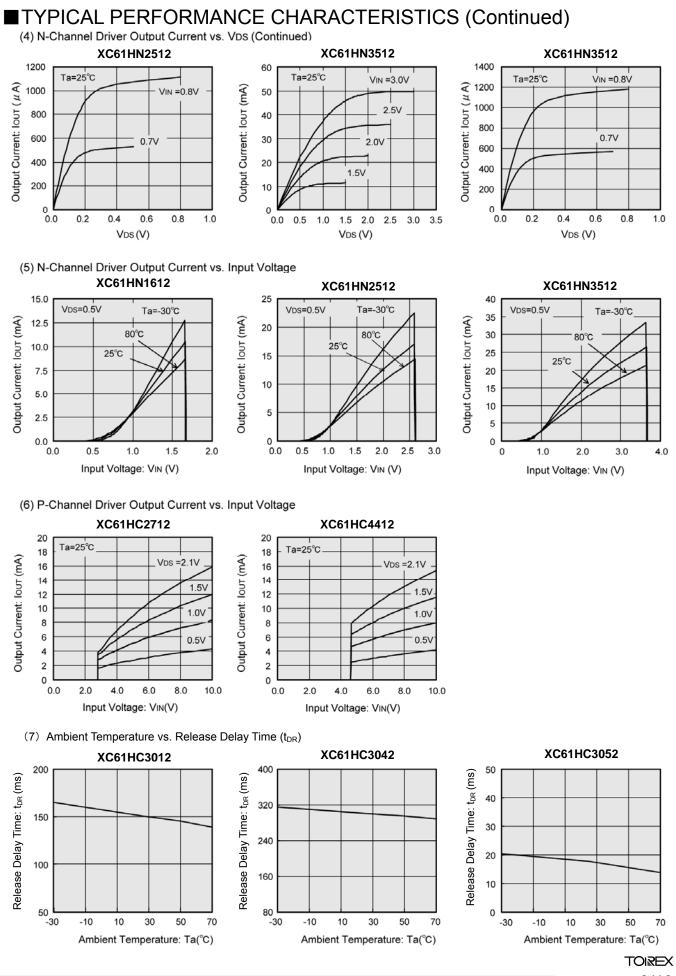
3

0

0.0

1.0V

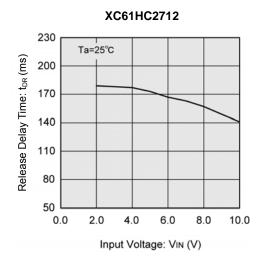
0.5



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■TYPICAL PERFORMANCE CHARACTERISTICS (Continued)

(8) Input Voltage vs. Release Delay Time (t_{DR})

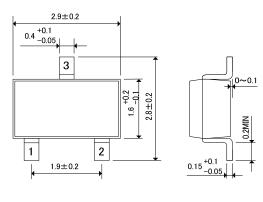


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■ PACKAGING INFORMATION

●SOT-23

(unit : mm)

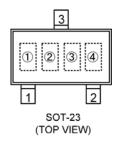




XC61H Series

■MARKING RULE

●SOT-23



1 represents product series

MARK	PRODUCTS SERIES
8	XC61H******-G

② standard : represents output configuration and integer number of detect voltage

CMOS output (XC61HC series)

MARK	VOLTAGE (V)
А	1. X
В	2. X
С	3. X
D	4. X
E	5. X
F	6. X

N-channel open drain (XC61HN series)

MARK	VOLTAGE (V)
Р	1. X
R	2. X
S	3. X
Т	4. X
U	5. X
V	6. X

③ represents decimal number of detect voltage and delay time.

DETECT	MARK					
VOLTAGE (V)	DELAY TIME 50ms~200ms (XC61H***1***-G)	DELAY TIME 80ms~400ms (XC61H***4***-G)	DELAY TIME 1ms~50ms (XC61H**5***-G)			
X.0	0	А	Ν			
X.1	1	В	Р			
X.2	2	С	R			
X.3	3	D	S			
X.4	4	E	Т			
X.5	5	F	U			
X.6	6	Н	V			
X.7	7	К	Х			
X.8	8	L	Y			
X.9	9	М	Z			

④ represents production lot number
0 to 9, A to Z or inverted characters of 0 to 9, A to Z repeated.
(G, I, J, O, Q,W excluded)

*No character inversion used.

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XC61HC1612MR-G	XC61HN2512MR-G	XC61HN1612MR-G	XC61HN4212MR-G	XC61HN3852MR-G
XC61HN4142MR-G	XC61HN2752MR-G	XC61HN1912MR-G	XC61HN3142MR-G	XC61HN2942MR-G
XC61HN3542MR-G	XC61HN2742MR-G	XC61HN4042MR-G	XC61HC2912MR-G	XC61HN3042MR-G
XC61HN2612MR-G	XC61HN3242MR-G	XC61HC4412MR-G	XC61HN2912MR-G	XC61HC2812MR-G
XC61HN2442MR-G	XC61HN4012MR-G	XC61HN4642MR-G	XC61HN5512MR-G	XC61HC2612MR-G